## Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

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Examiner

Art Unit

Cheng, Ichieh

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## **SEARCHED**

Class	Subclass	Date	Examiner
455	560,442,449,552.1,331,440,437,456.1.445,438,439	10/10/2007	Ichieh Cheng
370	349,338,329,412,389,469,395.2,236,428,351,436,395.21 ,401	10/10/2007	Ichieh Cheng

## **SEARCH NOTES**

Search Notes	Date	Examiner
Text search attached	10/10/2007	Ichieh Cheng

## INTERFERENCE SEARCH

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